

Solid State Devices, Inc.

14701 Firestone Blvd * La Mirada, Ca 90638 Phone: (562) 404-4474 * Fax: (562) 404-1773 ssdi@ssdi-power.com * www.ssdi-power.com

DESIGNER'S DATA SHEET

Part Number / Ordering Information ¹ SFFC50

Screening^{2/}
__ = Not Screened
TX = TX Level
TXV = TXV Level
S = S Level

Package S1 = SMD1

SFFC50S1

11 AMP, 600 Volts, 0.6 Ω N-Channel Power MOSFET

Features:

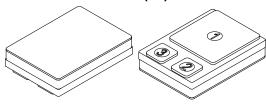
- Rugged Construction with Poly Silicon Gate
- Low RDS(on) and High Transconductance
- Excellent High Temperature Stability
- Very Fast Switching Speed
- Fast Recovery and Superior dv/dt Performance
- · Increased Reverse Energy Capability
- Low Input and Transfer Capacitance for Easy Paralleling
- Hermetically Sealed Surface Mount Package
- Low Inductance Package
- TX, TXV, S-Level Screening Available^{2/}

Maximum Ratings ^{3/}		Symbol	Value	Unit
Drain to Source Voltage		V _{DS}	600	V
Gate to Source Voltage		V _{GS}	±20	V
Continuous Drain Current	@ T _C = 25°C @ T _C = 100°C	I _{D1} I _{D2}	11 7	A
Operating & Storage Temperature		T _{OP} & T _{STG}	-55 to +150	°C
Thermal Resistance (Junction to Case)		R _{eJC}	1.25	°C/W
Total Power Dissipation	@ T _C = 25°C @ T _C = 55°C	P _D	100 76	w
Single Pulse Avalanche Energy		Eas	920	mJ
Repetitive Avalanche Energy		E _{AR}	18	mJ

NOTES: *Pulsed per MIL-STD-750.

- 1/ For ordering information, price, and availability contact factory.
- 2/ Screening based on MIL-PRF-19500. Screening flows available on request.
- 3/ Unless otherwise specified, all electrical characteristics @ 25°C.

SMD1 (S1)



NOTE: All specifications are subject to change without notification. SCD's for these devices should be reviewed by SSDI prior to release.

DATA SHEET #: F00297B

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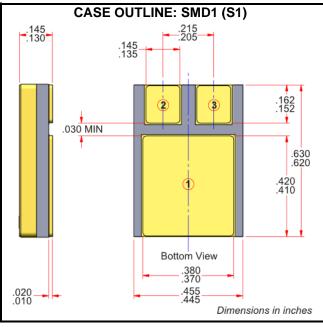


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SFFC50S1

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Electrical Characteristics3/		Symbol	Min	Тур	Max	Unit
Drain to Source Breakdown Voltage	V_{GS} = 0 V, I_D = 250 μA	BV _{DSS}	600	_		V
Temperature Coefficient of Breakdown Voltage		ΔBV _{DSS} ΔT _J		780		mV/°C
Drain to Source On State Resistance	$V_{GS} = 10 \text{ V}, I_D = 6 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 11 \text{ A}$	R _{DS(on)}	_	0.5 0.5	0.60 0.65	Ω
Gate Threshold Voltage	$V_{DS}=V_{GS},I_D=250\;\mu A$	$V_{GS(th)}$	2.0		4.0	V
Forward Transconductance	V _{DS} = V _{GS} , I _{DS} = 6 A	g _{fs}	5.7	13		S(O)
	= 80% rated voltage, V_{GS} = 0 V ted V_{DS} , V_{GS} = 0 V, T_A = 125°C	I _{DSS}	_	_	100 500	μΑ
Gate to Source Leakage Forward Gate to Source Leakage Reverse	At rated V _{GS}	I _{GSS}		_	100 -100	nA
Total Gate Charge Gate to Source Charge Gate to Drain Charge	V_{GS} = 10 V V_{DS} = 360 V Rated I _D	$oldsymbol{Q_{g}}{oldsymbol{Q_{gs}}} \ oldsymbol{Q_{gd}}$		100 11 56	140 20 69	nC
Turn on Delay Time Rise Time Turn off Delay Time Fall Time	V_{DD} = 50% rated VDS Rated I_{D} R _G = 6.2 Ω	$egin{array}{c} egin{array}{c} \egin{array}{c} \egin{array}{c} \egin{array}{c} \egin{array}$		21 10 65 18	30 20 100 25	nsec
Diode Forward Voltage I _S =	= rated I _D , V _{GS} = 0 V, T _J = 25°C	V _{SD}		_	1.4	V
Diode Reverse Recovery Time Reverse Recovery Charge	$T_J = 25$ °C, $I_F = \text{rated } I_D$, $di/dt = 100 \text{ A/}\mu\text{sec}$	t _{rr} Q _{rr}	_	450 3.9	830 —	nsec µC
Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{GS} = 0 \text{ V}$ $V_{DS} = 25 \text{ V}$ $f = 1 \text{ MHz}$	C _{iss} C _{oss} C _{rss}		2500 350 55		pF



PIN ASSIGNMENT (Standard)					
Package	Drain	Source	Gate		
SMD1	Pin 1	Pin 2	Pin 3		

NOTES:

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